European Conference on Neutron Scattering 2023



Contribution ID: 302 Type: Poster

Progress of MIRACLES experimental activities, the backscattering spectrometer at ESS

Monday, 20 March 2023 16:00 (2 hours)

MIRACLES is the neutron backscattering spectrometer of the European Spallation Source [1]. The instrument will display a flexible tuning of the energy resolution, that allows exploration of a broad range of timescales, from the nanosecond to the picosecond, along with an unprecedented wide dynamic range and a versatile selection of energies for quasielastic and inelastic scattering experiments in the cold neutron range. Our focus now is to describe how the scientific and technical requirements of the instrument are taking shape, with substantial progress in the development of design concepts for the neutron scattering components and experimental areas. Here, progress in the MIRACLES detector and data acquisition system, and evaluation of potential improvements in the analyzer system, that includes prototyping and testing measurements in the spectrometer IN16B at ILL, will be outlined. Furthermore, a description of the layout and ergonomics of the sample preparation areas will be detailed. These efforts will help to give final shape to the scattering system and the experimental station of the MIRACLES spectrometer.

[1] K. H. Andersen, et al., "The instrument suite of the European Spallation Source", Nucl. Instrum. & Meth. A 957, 163402 (2020).

Primary authors: ZUGAZAGA, Aitor (ESS Bilbao); CONDE, Alexander (ESS Bilbao); J. VILLACORTA, Félix (ESS Bilbao); HARPER, Giles (ESS Bilbao); BORDALLO, Heloisa (Niels Bohr Institute-University of Copenhagen / European Spallation Source); MAZKIARAN, Idoia (ESS Bilbao); Dr PEREIRA, Jose (ESS Bilbao); APPEL, Markus (Institut Laue-Langevin); CHRISTENSEN, Morten (European Spallation Source); G. DEL MORAL, Octavio (ESS Bilbao); MARTÍNEZ, Roberto (ESS Bilbao)

Presenter: Dr PEREIRA, Jose (ESS Bilbao)

Session Classification: Poster Session MONDAY

Track Classification: Neutron Instrumentation, Optics, Sample Environment, Detectors, and Soft-

ware